



SLOVENSKI STANDARD
SIST ISO 5436:2001

01-julij-2001

Vzorci za pomerjanje - Kontaktni instrumenti - Tipi, pomerjanje in uporaba vzorcev

Calibration specimens -- Stylus instruments -- Types, calibration and use of specimens

Échantillons d'étalonnage -- Instruments à palpeur -- Type, étalonnage et emploi des échantillons

(standards.iteh.ai)

Ta slovenski standard je istoveten z: ISO 5436:1985

<https://standards.iteh.ai/catalog/standards/sist/02e4b2cf-39f0-4863-92a3-fd8748d2dcc6/sist-iso-5436-2001>

ICS:

17.040.20 Lastnosti površin Properties of surfaces

SIST ISO 5436:2001

en

iTeh STANDARD PREVIEW
(standards.iteh.ai)

SIST ISO 5436:2001

<https://standards.iteh.ai/catalog/standards/sist/02e4b2cf-39f0-4863-92a3-fd8748d2dcc6/sist-iso-5436-2001>

International Standard



5436

INTERNATIONAL ORGANIZATION FOR STANDARDIZATION • МЕЖДУНАРОДНАЯ ОРГАНИЗАЦИЯ ПО СТАНДАРТИЗАЦИИ • ORGANISATION INTERNATIONALE DE NORMALISATION

Calibration specimens — Stylus instruments — Types, calibration and use of specimens

Échantillons d'étalonnage — Instruments à palpeur — Type, étalonnage et emploi des échantillons

First edition — 1985-09-01

ITeH STANDARD PREVIEW
(standards.iteh.ai)

[SIST ISO 5436:2001](https://standards.iteh.ai/catalog/standards/sist/02e4b2cf-39f0-4863-92a3-fd8748d2dcc6/sist-iso-5436-2001)

<https://standards.iteh.ai/catalog/standards/sist/02e4b2cf-39f0-4863-92a3-fd8748d2dcc6/sist-iso-5436-2001>

UDC 53.089.68

Ref. No. ISO 5436-1985 (E)

Descriptors : surface condition, roughness, roughness measurement, measuring instruments, profile meters, calibration, reference sample, specifications, dimensions, marking.

Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work.

Draft International Standards adopted by the technical committees are circulated to the member bodies for approval before their acceptance as International Standards by the ISO Council. They are approved in accordance with ISO procedures requiring at least 75 % approval by the member bodies voting.

International Standard ISO 5436 was prepared by Technical Committee ISO/TC 57, *Metrology and properties of surfaces*.

ITeH STANDARD PREVIEW
(standards.iteh.ai)

[SIST ISO 5436:2001](https://standards.iteh.ai/catalog/standards/sist/02e4b2cf-39f0-4863-92a3-fd8748d2dcc6/sist-iso-5436-2001)

<https://standards.iteh.ai/catalog/standards/sist/02e4b2cf-39f0-4863-92a3-fd8748d2dcc6/sist-iso-5436-2001>

Calibration specimens — Stylus instruments — Types, calibration and use of specimens

1 Scope and field of application

This International Standard specifies the characteristics of specimens for the calibration of stylus instruments (see ISO 1880 and ISO 3274) and the annexes give information regarding their calibration and application to the calibration and adjustment in laboratories, standards rooms and workshops.

2 References

ISO 468, *Surface roughness — Parameters, their values and general rules for specifying requirements*.

ISO 1878, *Classification of instruments and devices for measurement and evaluation of the geometrical parameters of surface finish*.

ISO 1879, *Instruments for the measurement of surface roughness by the profile method — Vocabulary*.

ISO 1880, *Instruments for the measurement of surface roughness by the profile method — Contact (stylus) instruments of progressive profile transformation — Profile recording instruments*.

ISO 3274, *Instruments for the measurement of surface roughness by the profile method — Contact (stylus) instruments of consecutive profile transformation — Contact profile meters, system M*.

3 Definitions

For the purposes of this International Standard, the definitions given in ISO 468, ISO 1878, ISO 1879 and ISO 3274, and the following apply.

standard instrument calibration specimen: A specimen having accurately determined standardized characteristics for testing or establishing one or more features of the performance of an instrument.

4 Types and purposes of instrument calibration specimens

The calibration of the existing wide range of instruments in all modes of operation calls for more than one type of calibration specimen.

Each calibrated specimen may have a limited range of application according to its own characteristics and those of the instrument to be calibrated. The validity of the calibration of an instrument will be dependent on the correct association of these characteristics.

To cover the range of requirements, four types of specimens are described, each of which may have a number of variants. Their principal applications are specified in 4.1 to 4.4 and dimensions and tolerances in 7.1 to 7.4.

4.1 Type A

These specimens are for checking the vertical magnification of profile recording instruments having displacement sensitive pick-ups.

4.1.1 Type A1

These specimens have a wide calibrated groove with a flat bottom, or a number of separated grooves of equal or increasing depth, each groove being wide enough to be insensitive to the shape or condition of the stylus tip.

4.1.2 Type A2

These specimens are similar to type A1, except that the grooves have rounded bottoms of sufficient radius to be insensitive to the shape or condition of the stylus tip.

4.2 Type B

These specimens are primarily for checking the condition of the stylus tip.

4.2.1 Type B1

These specimens have a narrow groove or a number of separated grooves proportioned to be increasingly sensitive to the dimensions of the stylus. They are intended for use with instruments having displacement sensitive pick-ups.

4.2.2 Type B2

These specimens have two grids of nominally equal R_a values, one being sensitive and the other insensitive to the dimensions of the stylus tip. These grids are used comparatively for check-

ISO 5436-1985 (E)

ing the stylus tips of parameter instruments having motion-sensitive pick-ups, the ratio of the R_a values being taken as the criterion.

4.3 Type C

These specimens are primarily intended for checking parameter meters.

They have a grid of repetitive grooves of simple shape (either sinusoidal, triangular or arcuate) which have relatively low harmonic amplitudes. They are used primarily for calibrating parameter meters, but they may also be used for checking horizontal magnification if the spacing of the grooves is held within limits acceptable for this purpose.

An essential requirement of type C calibration specimens is that standardized specimens of differing waveform are nevertheless compatible, in the sense that they will all lead to the same state of instrument calibration or verification, provided they are used correctly.

The declared parameter values issued with each specimen refer to a smooth straight datum and filtered profiles derived from the trace according to ISO 3274. Although the wider grooves are generally insensitive to the dimensions of the stylus tip, sensitivity in this respect may become appreciable for the narrowest grooves; and for this reason the parameter values shall be declared with reference to the stylus tip.

4.3.1 Use for skidless instruments

Each specimen will calibrate a skidless instrument (one which traces the profile with respect to a smooth straight datum) with respect to the particular crest spacing of that specimen.

The purpose of the series of specimens is to enable the transmission characteristic to be checked for a number of spacings and amplitudes.

4.3.2 Use for skid-type instruments

The use of type C specimens for calibrating skid-type instruments is restricted to those for which the generally indeterminate rise and fall of the skid(s) over the crests makes an insignificant contribution to the calibration. This is best assured by using a specimen having the shortest crest spacing permitted by the stylus, as shown in annex B, and this is the general practice.

4.4 Type D

These specimens are for overall check of meter calibration.

They have irregular profiles (for example as obtained by grinding) in the direction of traverse, but they have the convenience of an approximately constant cross-section along their lengths.

The specimens simulate workpieces containing a wide range of crest spacings, but reduce the number of traverses needed to give a good average value. They provide, for reassurance, a final overall check on calibration.

The accuracy obtainable by averaging a few random traverses will generally be less than type C specimens, but may be sufficient for workshop purposes. Higher accuracy can be obtained by averaging a statistically determined number of appropriately positioned traverses.¹⁾

5 Materials

The material used shall be hard enough to ensure adequate life in relation to cost. Its surface shall be smooth and flat enough not to affect the evaluation of the grooves. Glass or quartz or materials harder than 750 HV are favoured.

6 Size of specimen

The operative area shall be large enough to provide for the total length of traverse required for all intended determinations.

One or more than one kind of specimen may be provided on a single block. So as to ensure the best possible economic conditions, overall dimensions of specimens are not given.

7 Mechanical requirements

It should be noted that, in the tables which follow, the nominal values carry a wide tolerance, and that these values should not be used as the basis of instrument calibration (see clause 9, notes 1 and 2).

7.1 Type A

7.1.1 Type A1: Wide grooves with flat bottoms (see figure 1 and table 1)

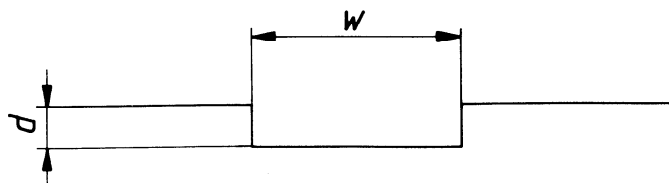


Figure 1 — Type A1 groove

1) To form the subject of a future International Standard.

Table 1 – Nominal values of depth and width for type A1

Values in micrometres

Depth, d	0,3	1,0	3,0	10	30	100
Width, w	100	100	200	200	500	500

If a skid is used, it shall not cross a groove at the same time that the stylus crosses the groove being measured.

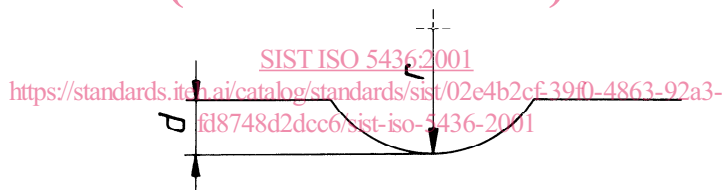
For tolerances, see table 2.

Table 2 – Tolerances for types A1 and A2

Nominal value	Tolerance on nominal value	Uncertainty of measurement in calibrated mean depth	Standard deviation from the calibrated mean
μm	%	% (μm)	%
0,3	± 20	± 3 ($\pm 0,01$)	3
1	± 15	± 2 ($\pm 0,02$)	2
3	± 10	± 2 ($\pm 0,06$)	2
10	± 10	± 2 ($\pm 0,2$)	2
30	± 10	± 2 ($\pm 0,6$)	2
100	± 10	± 2 (± 2)	2

iTeh STANDARD PREVIEW

7.1.2 Type A2: Wide grooves with rounded bottoms (see figure 2 and table 3)

**Figure 2 – Type A2 groove****Table 3 – Nominal values of depth and radius for type A2**

Depth, d , (μm)	1,0	3,0	10	30	100
Radius, r , (mm)	1,5	1,5	1,5	0,75	0,75

If a skid is used, it shall not cross the groove at the same time that the stylus crosses the groove being measured.

For tolerances, see table 2.

7.1.3 The basis of assessment for types A1 and A2 is given in 8.1; requirements regarding statements of mean values are given in clause 9; guidance on calibration is given in clauses A.1 and A.2; guidance on use is given in clauses B.1 and B.2.

7.2 Type B grooves for checking stylus tips

7.2.1 Type B1

Development of specimens having single narrow grooves is proceeding, but is not yet sufficiently advanced to permit standardization.

7.2.2 Type B2

These specimens have two grids formed on a common base.

ISO 5436-1985 (E)

7.2.2.1 Sensitive grid (see figure 3)

Isosceles triangular grooves with sharp peaks and valleys, for testing 10 μm radius tips.

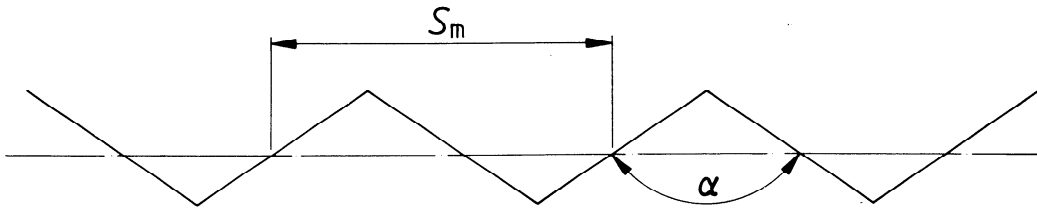


Figure 3 — Type B2 grooves (sensitive grid)

For 10 μm radius tips :

- $\alpha = 150^\circ$
- $R_a = 0,5 \mu\text{m} \pm 5 \%$

S_m shall be determined by α and R_a , and will thus have the mid-limit value of 15 μm .

For tolerances, see table 4.

7.2.2.2 Insensitive grid (see figure 4)

Sinusoidal or arcuate grooves, proportioned to make R_a substantially independent of the stylus tip.



Figure 4 — Type B2 grooves (insensitive grid)

For 10 μm radius tips :

- $R_a = 0,5 \mu\text{m} \pm 5 \%$
- $S_m = 0,25 \text{ mm}$

For tolerances, see table 4.

NOTES

- 1 Grooves for tips with a radius of less than 10 μm (if such are practical) have still to be developed.
- 2 For convenience, one or more type C grids may be added for general calibration of R_a . Such grids shall be clearly distinguished from the type B2 pair.

7.2.3 The basis of assessment for type B2 is given in 8.2, tolerances are given in 7.2.2 and table 4, and the method of use is described in B.4.

Table 4 — Tolerances for type B2 sensitive and insensitive grids

Nominal value		Tolerance on nominal value
for sensitive grids	for insensitive grids	
		%
$\alpha = 150^\circ$		± 5
$R_a = 0,5 \mu\text{m}$	$R_a = 0,5 \mu\text{m}$	
$S_m = 15 \mu\text{m}$	$S_m = 0,25 \text{ mm}$	
Ratio of mean R_a values		± 2

7.3 Type C

The nominal values given in 7.3.1, 7.3.2 and 7.3.4 are values which assume negligible attenuation by the stylus or filter.

7.3.1 Type C1: Grooves having a sine wave profile (see figure 5 and table 5)

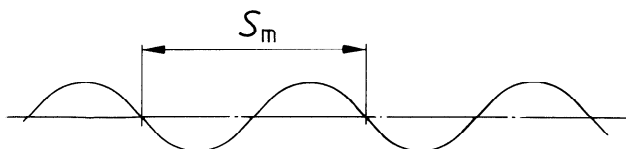


Figure 5 — Type C1 grooves

Table 5 — Nominal values of R_a for type C1

Mean spacing of profile irregularities, S_m , mm			
0,08	0,25	0,8	2,5
R_a , μm			
0,1	0,3	1	3
0,3	1	3	10
1	3	10	30
3	10	30	—

For tolerances, see table 6.

SIST ISO 5436:2001

<https://standards.iteh.ai/catalog/standards/sist/02e4b2cf-39f0-4863-92a3-1d0748d2dccc/sist-iso-5436-2001>

Table 6 — Tolerances for types C1 to C4

Nominal value of R_a	Tolerance on nominal value	Uncertainty of measurement of stated mean value of R_a	Standard deviation from mean value
μm	%	%	%
0,1	± 25	± 3	3
0,3	± 20	± 2	2
1	± 15	± 2	2
3	± 10	± 2	2
10	± 10	± 2	2
30	± 10	± 2	2

NOTE — The sine wave provides an ideal reference for calibrating a frequency-dependent instrument because the perfect sine wave, having no harmonics, is not changed in shape by a wave filter and accords directly with the transmission characteristics defined in ISO 3274.

7.3.2 Type C2: Grooves having an isosceles triangular profile (see figure 6 and table 7)

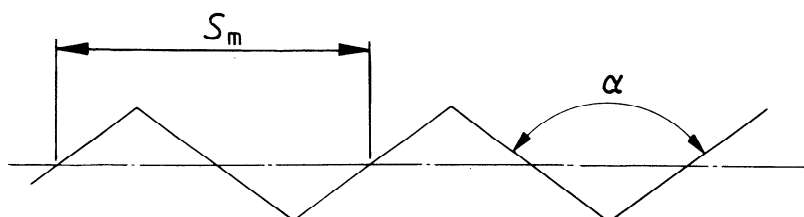


Figure 6 — Type C2 grooves

ISO 5436-1985 (E)

Table 7 – Nominal values of R_a and α for type C2

Mean spacing of profile irregularities, S_m , mm				α°
0,08	0,25	0,8	2,5	
R_a , μm				
0,1	0,3	1,0	3	178,9
0,3	1,0	3	10	176,4
1,0	3	10	30	168,6
3	10	30	—	144,5

For tolerances, see table 6.

7.3.3 Type C3: Simulated sine wave grooves (see figure 7)

These are simulated sine waves, which include triangular profiles with rounded or truncated peaks and valleys, the total r.m.s. harmonic content of which shall not exceed 10 % of the r.m.s. value of the fundamental.

For tolerances, see table 6.



Figure 7 – Type C3 grooves

NOTE — Specimens of this kind have often been provided by instrument manufacturers for calibrating their own instruments, but without commitment regarding the further use of the specimens.

(standards.iteh.ai)

7.3.4 Type C4: Grooves having an arcuate profile (see figure 8 and table 8)

SIST ISO 5436:2001

<https://standards.iteh.ai/catalog/standards/sist/02e4b2cf-39f0-4863-92a3-118748d2dcc6/sist-iso-5436-2001>

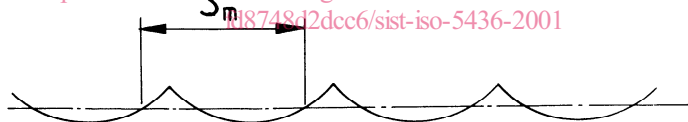


Figure 8 – Type C4 grooves

Table 8 – Nominal unfiltered values of R_a for type C4

Mean spacing of profile irregularities, S_m , mm	
0,25	0,8
R_a , μm	
0,2	3,2
3,2	6,3
6,3	12,5
12,5	25

For tolerances, see table 6.

7.4 Type D: Unidirectional irregular profiles (see figure 9)

These have an irregular ground profile which is repeated every 4 mm in the longitudinal direction of the specimen. Normal to the measuring direction of the specimens, the production grooves on the measuring area have a constant profile form.

The nominal filtered values, R_a , of the specimens, in micrometres, are

0,15; 0,5; 1,5 (cut-off value 0,8 mm)

For tolerances, see table 9.

Table 9 — Tolerances for type D

Nominal value R_a	Tolerance on nominal value	Uncertainty of measurement of stated mean value of R_a ¹⁾	Standard deviation from mean value
μm	%	%	%
0,15	± 30	± 5	4
0,5	± 20	± 3	3
1,5	± 15	± 3	3

1) From 12 evenly distributed readings.

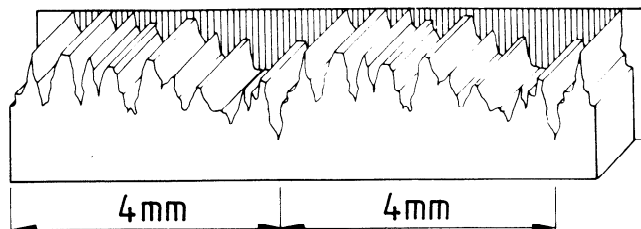


Figure 9 — Type D grooves (profile repetition at 4 mm intervals)

7.5 The basis of assessment for types C and D is given in 8.3. Guidance on calibration is dealt with in clause A.3, while clauses B.3 to B.6 refer to use and other relevant matters.

The depth d of the groove shall be assessed perpendicularly from the upper mean line to the mid-point of the lower mean line.

8 Basis of assessment of calibrated values

NOTE — The depth d as defined here will be equal to the mean of the portion C below the upper mean line.

8.1 Type A

A significant number, not less than five, of evenly distributed traces shall be taken.

8.1.1 Type A1

A continuous straight mean line equal in length to three times the width of the groove is drawn over the groove to represent the upper level of the surface and another to represent the lower level, both lines extending symmetrically about the centre of the groove (see figure 10).

To avoid the influence of any rounding of the corners, the upper surface on each side of the groove is to be ignored for a length equal to one-third of the width of the groove. The surface at the bottom of the groove is assessed only over the central third of its width. The portions to be used for assessment purposes are therefore those shown at A, B and C in figure 10.

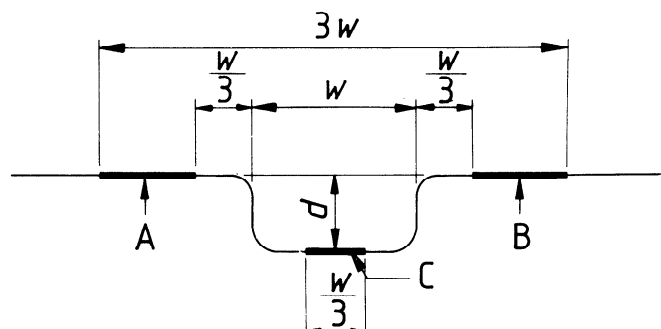


Figure 10 — Assessment of calibrated values for type A1

A significant number, not less than five, of evenly distributed traces shall be taken.

8.1.2 Type A2

A mean line representing the upper level is drawn over the groove as described for type A1. The depth shall be assessed from the upper mean line to the lowest point of the groove.

A significant number, not less than five, of evenly distributed traces shall be taken.

8.2 Type B2

The ratio of the mean R_a of the sensitive grid and the mean R_a of the insensitive grid shall be calibrated using a substantially sharp tip ($< 2 \mu\text{m}$ nominal radius) and a standard two C-R¹⁾ filter having 0,25 mm cut-off according to ISO 3274. (See clause B.4.)

Not less than 18 evenly distributed traces shall be taken on each grid, all instrument adjustments remaining constant throughout the determination.

8.3 Types C1 to C4, and D

The profile shall be traced by one or more specified stylus tips with respect to a straight datum, and an R_a value shall be determined, by measurement or computation, after modification of

1) "C" stands for "capacitive", "R" for "resistive".